


<b>Search Notes</b>  	<b>Application/Control No.</b>  10582814	<b>Applicant(s)/Patent Under Reexamination</b>  MEIER ET AL.
	<b>Examiner</b>  SANG KIM	<b>Art Unit</b>  3654

SEARCHED			
Class	Subclass	Date	Examiner
242	597.1-.2, .597.4-.6, 608.5, 578, 118.61	4/8/08	SK
Updated all above		9/17/08	SK

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
see search printout		9/17/08	SK

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